N-channel 30 V 1.3 m Ω logic level MOSFET in LFPAK

Rev. 02 — 25 June 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel MOSFET in LFPAK package qualified to 150 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

1.2 Features and benefits

- Advanced TrenchMOS provides low RDSon and low gate charge
- High efficiency gains in switching power convertors

1.3 Applications

- DC-to-DC converters
- Lithium-ion battery protection
- Load switching

1.4 Quick reference data

Table 1. Quick reference

- Improved mechanical and thermal characteristics
- LFPAK provides maximum power density in a Power SO8 package
- Motor control
- Server power supplies

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$		-	-	30	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V};$ see <u>Figure 1</u> ;	[1]	-	-	100	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	121	W
Tj	junction temperature			-55	-	150	°C
Avalanc	he ruggedness						
E _{DS(AL)S}	non-repetitive drain-source avalanche energy			-	-	383	mJ
Dynamic characteristics							
Q_{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$		-	9.3	-	nC
Q _{G(tot)}	total gate charge	$V_{DS} = 12 V$; see <u>Figure 13</u> ; see <u>Figure 14</u>		-	46.6	-	nC



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Table 1.	Quick reference	.continued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	naracteristics					
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I _D = 15 A; T _j = 100 °C; see <u>Figure 12</u>	-	-	1.8	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 17</u>	-	1.04	1.3	mΩ

[1] Continuous current is limited by package.

2. Pinning information

Table 2.	Pinning	information				
Pin	Symbol	Description	Simplified outline	Graphic symbol		
1	S	source		_		
2	S	source				
3	S	source				
4	G	gate				
mb	D	mounting base; connected to drain	SOT1023 (LFPAK2)	mbb076 S		

3. Ordering information

Table 3. Ordering information

Type number	Package			
	Name	Description	Version	
PSMN1R3-30YL	LFPAK2	Plastic single-ende surface-mounted package (LFPAK2); 4 leads	SOT1023	

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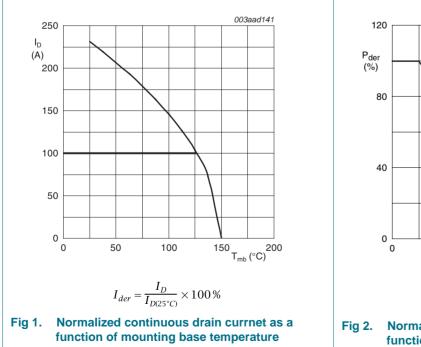
4. Limiting values

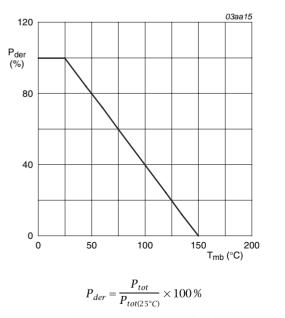
Table 4.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C		-	30	V
V _{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	30	V
V _{GS}	gate-source voltage			-20	20	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	[1]	-	100	А
		V_{GS} = 10 V; T_{mb} = 25 °C; see <u>Figure 1</u>	[1]	-	100	А
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3		-	923	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	121	W
T _{stg}	storage temperature			-55	150	°C
Tj	junction temperature			-55	150	°C
T _{sld(M)}	peak soldering temperature			-	260	°C
Source-dr	ain diode					
I _S	source current	T _{mb} = 25 °C;	[1]	-	100	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	923	А
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_{D} = 100 A; V_{sup} \leq 30 V; R_{GS} = 50 $\Omega;$ unclamped		-	383	mJ

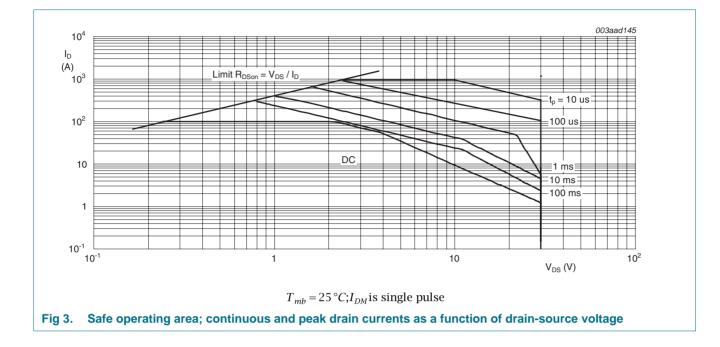
[1] Continuous current is limited by package.







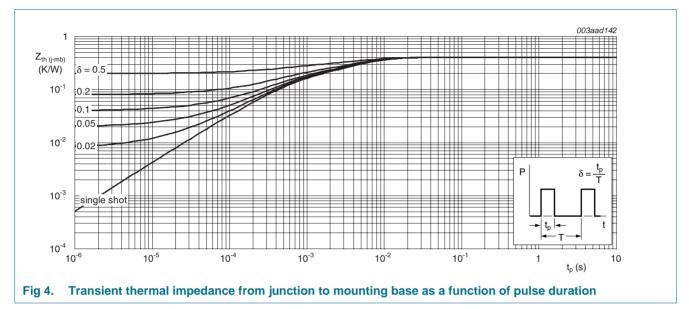
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5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	see <u>Figure 4</u>	-	0.4	1.03	K/W



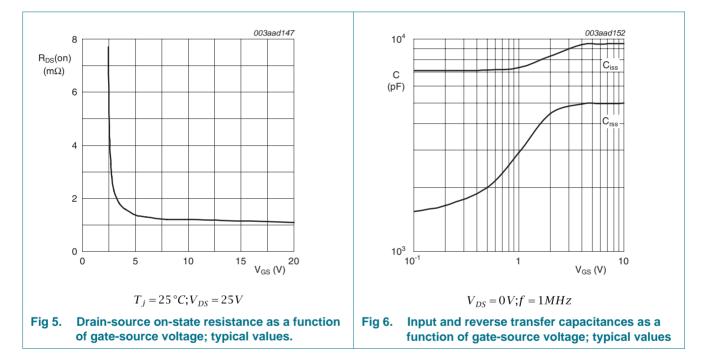
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6. Characteristics

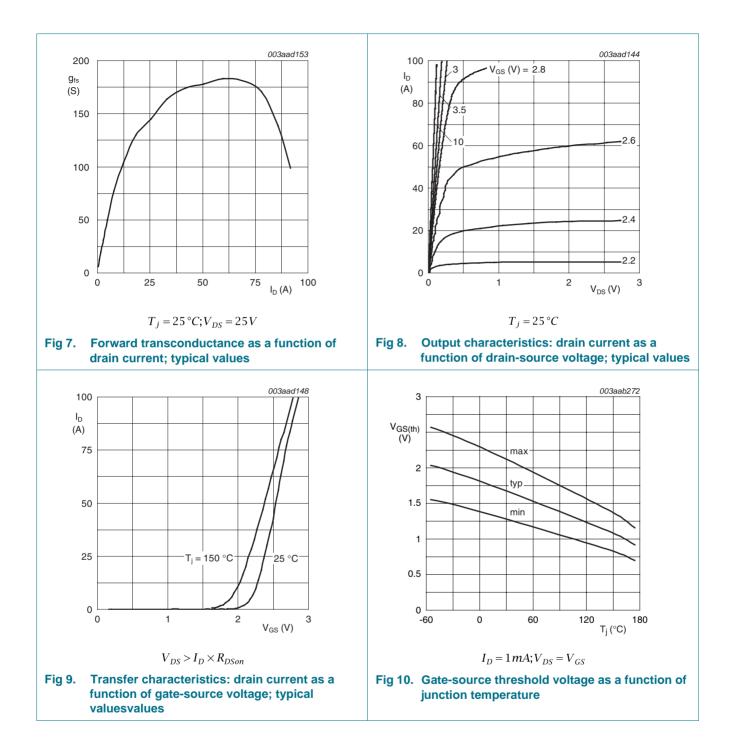
Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ C$	30	-	-	V
	breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ C$	27	-	-	V
V _{GS(th)}	gate-source threshold voltage	I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 25 °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	1.3	1.7	2.15	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 150 °C; see <u>Figure 10</u>	0.65	-	-	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; see <u>Figure 10</u>	-	-	2.45	V
DSS	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
IGSS	gate leakage current	V_{GS} = 15 V; V_{DS} = 0 V; T_j = 25 °C	-	-	100	nA
		V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C	-	-	100	nA
R _{DSon}	drain-source on-state resistance	V _{GS} = 4.5 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 17</u>	-	1.43	1.95	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 100 °C; see <u>Figure 12</u>	-	-	1.8	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 150 °C; see <u>Figure 12</u>	-	1.9	2.8	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 17</u>	-	1.04	1.3	mΩ
R _G	gate resistance	f = 1 MHz	-	0.89	-	Ω
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	100	-	nC
		$I_D = 0 \text{ A}; \text{ V}_{DS} = 0 \text{ V}; \text{ V}_{GS} = 10 \text{ V}$	-	90	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	46.6	-	nC
Q _{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	17.9	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	I_D = 25 A; V_{DS} = 12 V; V_{GS} = 4.5 V; see <u>Figure 13</u>	-	11	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	6.9	-	nC
Q _{GD}	gate-drain charge	I_D = 25 A; V_{DS} = 12 V; V_{GS} = 4.5 V; see <u>Figure 13</u> ; see <u>Figure 14</u>	-	9.3	-	nC
/ _{GS(pl)}	gate-source plateau voltage	V _{DS} = 12 V; see <u>Figure 13</u> ; see <u>Figure 14</u>	-	2.53	-	V
C _{iss}	input capacitance	V_{DS} = 12 V; V_{GS} = 0 V; f = 1 MHz;	-	6227	-	pF
C _{oss}	output capacitance	$T_j = 25 \text{ °C}; \text{ see } Figure 15$	-	1415	-	pF
C _{rss}	reverse transfer capacitance		-	619	-	pF

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Table 6.	Characteristics continued						
Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
t _{d(on)}	turn-on delay time	V_{DS} = 12 V; R_L = 0.5 $\Omega;$ V_{GS} = 4.5 V;	-	64	-	ns	
t _r	rise time	$R_{G(ext)} = 5.6 \Omega$	-	108	-	ns	
t _{d(off)}	turn-off delay time		-	106	-	ns	
t _f	fall time		-	52	-	ns	
Source-d	rain diode						
V_{SD}	source-drain voltage	I _S = 25 A; V _{GS} = 0 V; T _j = 25 °C; see <u>Figure 16</u>	-	0.88	1.2	V	
t _{rr}	reverse recovery time	$I_{S} = 20 \text{ A}; \text{ d}I_{S}/\text{d}t = -100 \text{ A/s}; \text{ V}_{GS} = 0 \text{ V};$	-	46	-	ns	
Qr	recovered charge	$V_{DS} = 20 V$	-	53	-	nC	

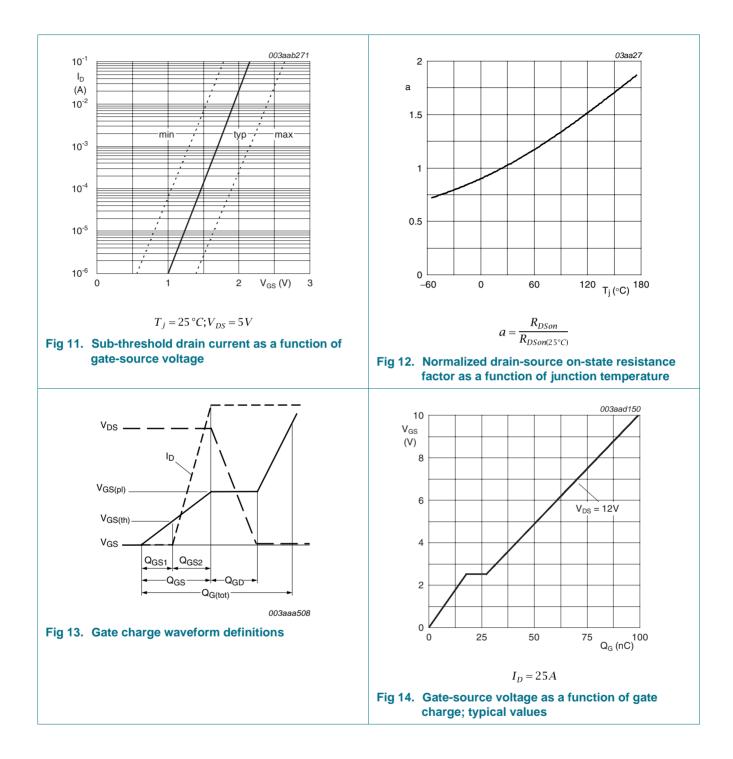


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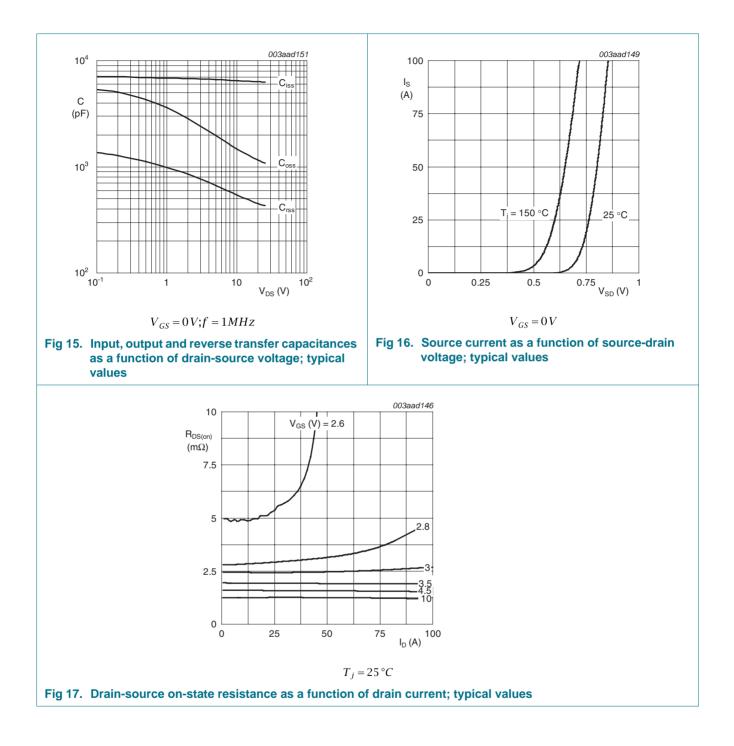


PSMN1R3-30YL_2

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7. Package outline

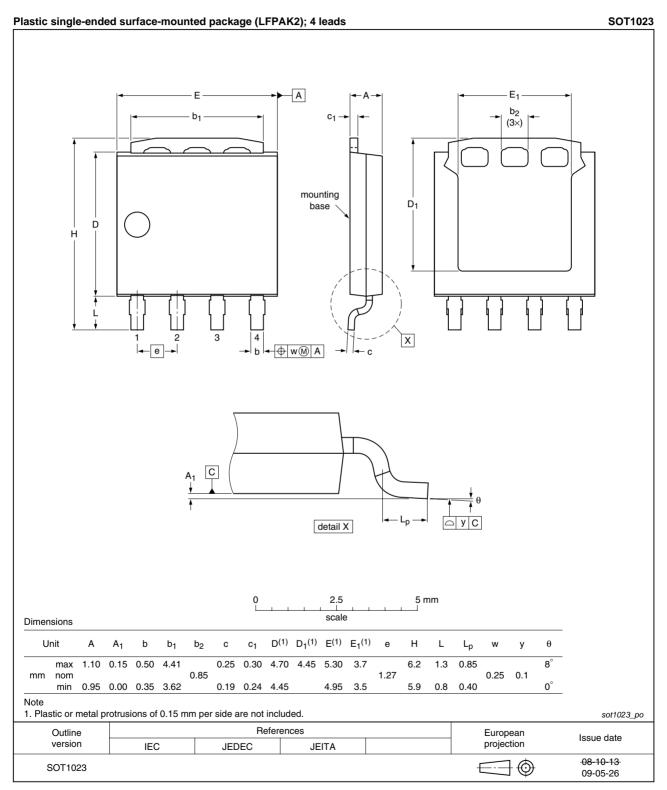


Fig 18. Package outline SOT1023; Package outline

PSMN1R3-30YL_2

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8. Revision history

Table 7.Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN1R3-30YL_2	20090625	Product data sheet	-	PSMN2R3-30YL_1
Modifications:	 Status char 	nged from objective to pr	oduct.	
	 Various cha 	anges to content.		
PSMN1R3-30YL_1	20090528	Objective data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions"

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